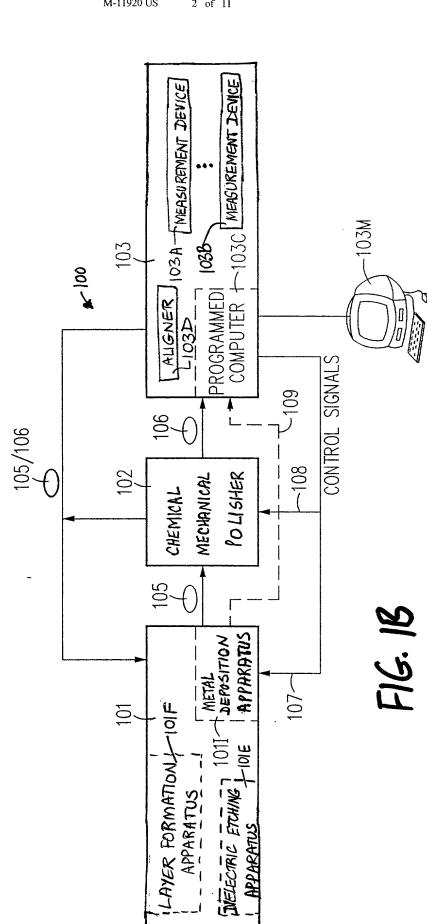
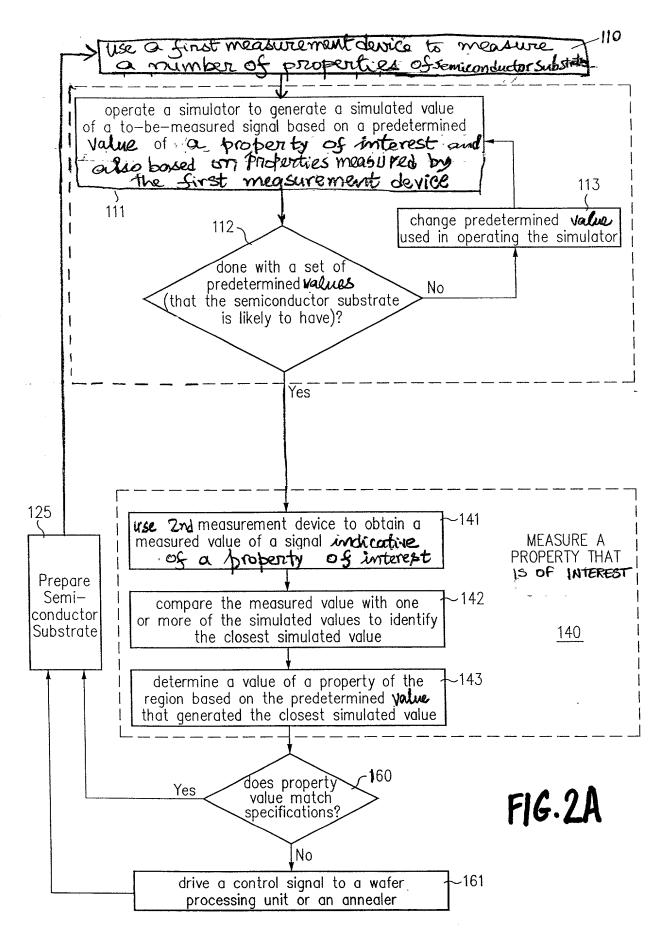
fabricate a portion of a workpiece 10 ~90 by forming a layer, e.g. of oxide or metal or semiconductor followed by etching or ion implantation use first measurement device to make first measurement by a first process ti Use second measurement device to make second measurement by a second process Combine both measurements together to determine a value of a property of the workpiece being fabricated 60 match all sites on Workpiece/ YES Specifications NO drive a Control signal to Sabrication unit

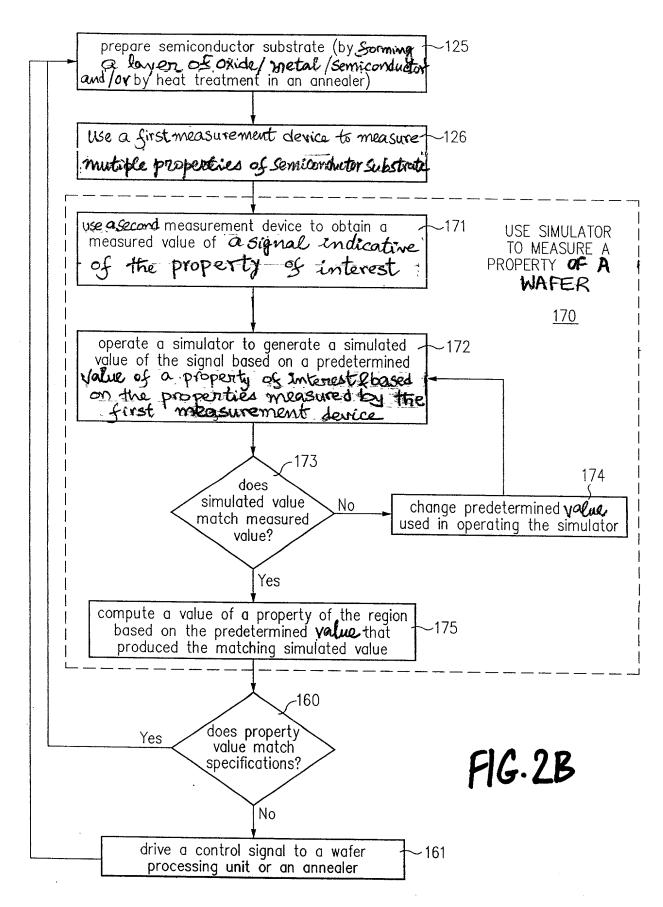
FIG. 1A

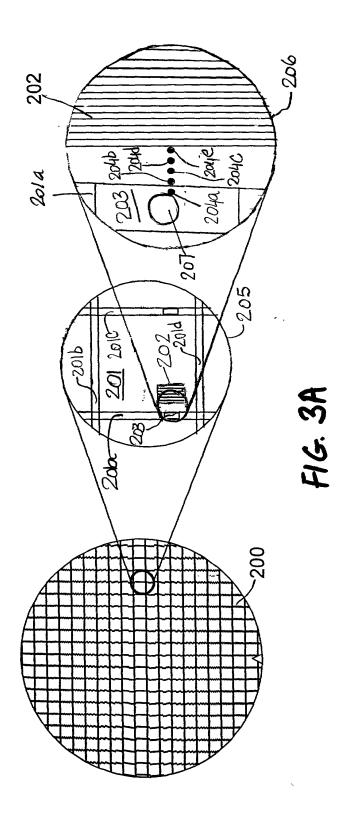


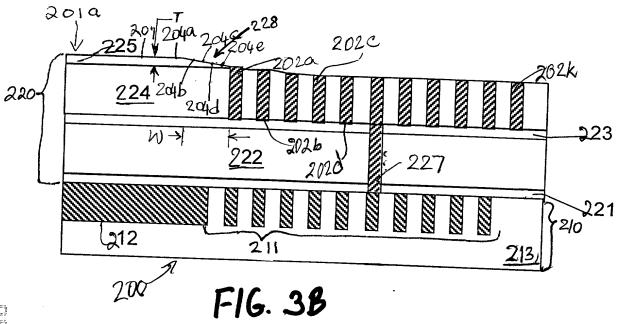


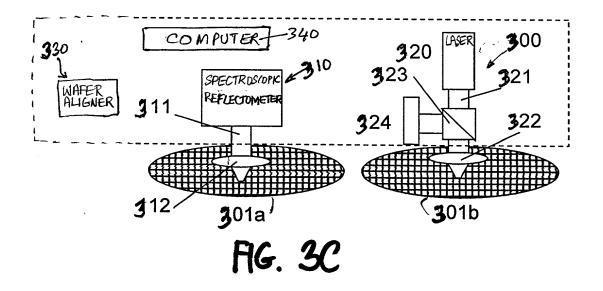


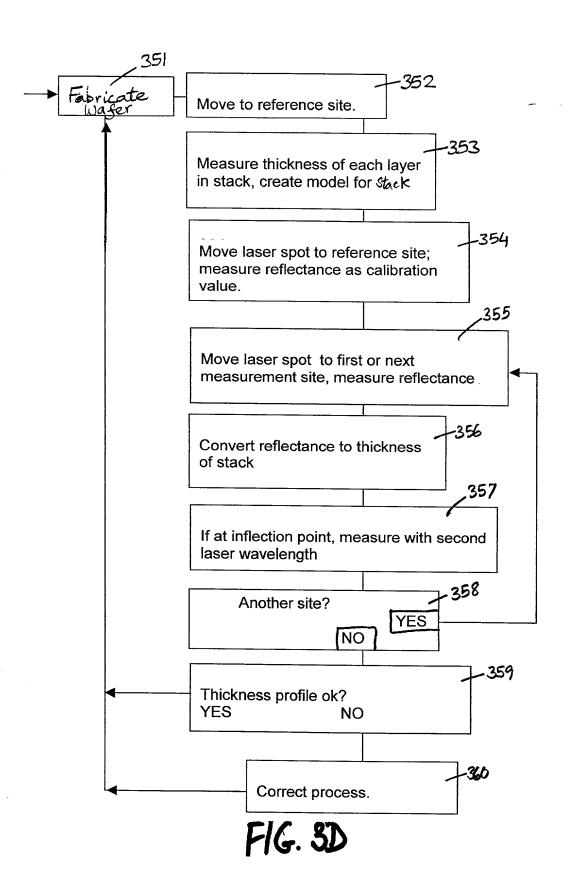




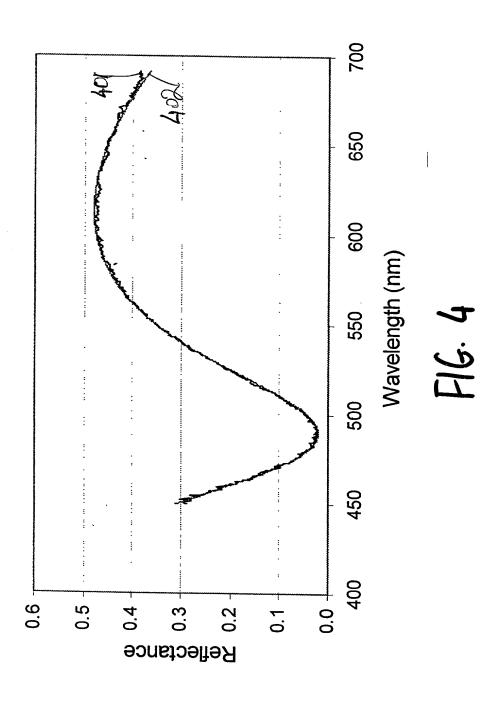


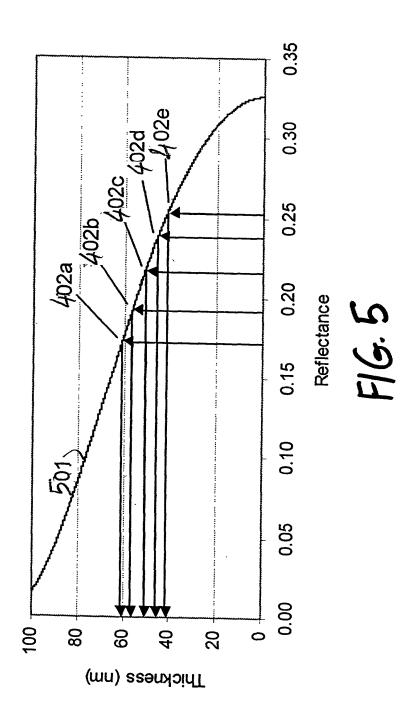




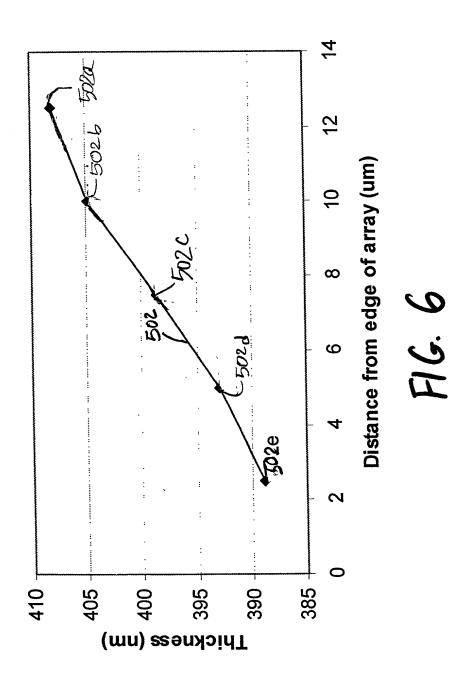












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